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Kind regards,

Team Nexperia



# PBSS304ND

# 80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor Rev. 02 — 17 December 2007

**Product data sheet** 

### **Product profile**

#### 1.1 General description

NPN low V<sub>CEsat</sub> Breakthrough In Small Signal (BISS) transistor in a SOT457 (SC-74) small Surface-Mounted Device (SMD) plastic package.

PNP complement: PBSS304PD.

#### 1.2 Features

- Low collector-emitter saturation voltage V<sub>CEsat</sub>
- High collector current capability I<sub>C</sub> and I<sub>CM</sub>
- High collector current gain (h<sub>FE</sub>) at high I<sub>C</sub>
- High efficiency due to less heat generation
- Smaller required Printed-Circuit Board (PCB) area than for conventional transistors

#### 1.3 Applications

- High-voltage DC-to-DC conversion
- High-voltage MOSFET gate driving
- High-voltage motor control
- High-voltage power switches (e.g. motors, fans)
- Thin Film Transistor (TFT) backlight inverter
- Automotive applications

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{CEO}$	collector-emitter voltage	open base		-	-	80	V
I <sub>C</sub>	collector current		[1]	-	-	3	Α
$I_{CM}$	peak collector current	single pulse; $t_p \le 1 \text{ ms}$		-	-	6	Α
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_C = 2 A;$ $I_B = 200 \text{ mA}$	[2]	-	68	88	mΩ

<sup>[1]</sup> Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.



<sup>[2]</sup> Pulse test:  $t_p \le 300 \ \mu s$ ;  $\delta \le 0.02$ .

80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

#### **Pinning information** 2.

Table 2. **Pinning** 

Pin	Description	Simplified outline	Symbol
1	collector	D. D. D.	
2	collector	<u> </u>	1, 2, 5, 6 
3	base	0	3 —
4	emitter	1 12 13	4
5	collector		sym014
6	collector		eye.r

# **Ordering information**

Table 3. **Ordering information** 

Type number	Package		
	Name	Description	Version
PBSS304ND	SC-74	plastic surface-mounted package (TSOP6); 6 leads	SOT457

#### **Marking** 4.

Table 4. **Marking codes** 

Type number	Marking code
PBSS304ND	AF

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### 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CBO}$	collector-base voltage	open emitter	-	80	V
$V_{CEO}$	collector-emitter voltage	open base	-	80	V
$V_{EBO}$	emitter-base voltage	open collector	-	5	V
$I_{C}$	collector current		<u>[1]</u> -	1	Α
			[2] -	3	Α
I <sub>CM</sub>	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	6	Α
I <sub>B</sub>	base current		-	8.0	Α
I <sub>BM</sub>	peak base current	single pulse; $t_p \le 1 \text{ ms}$	-	2	Α
P <sub>tot</sub>	total power dissipation	$T_{amb} \le 25  ^{\circ}C$	<u>[1]</u> _	360	mW
			<u>[3]</u> _	600	mW
			<u>[4]</u> _	750	mW
			[2] -	1.1	W
			[1][5]	2.5	W
$T_j$	junction temperature		-	150	°C
$T_{amb}$	ambient temperature		-65	+150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

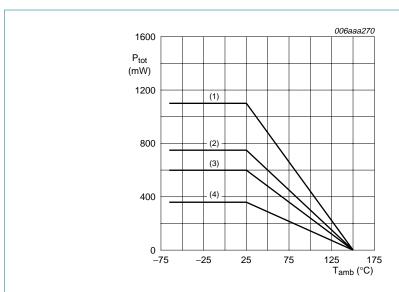
<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

<sup>[2]</sup> Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.

<sup>[3]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.

<sup>[4]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.

<sup>[5]</sup> Pulse test:  $t_p \le 10$  ms;  $\delta \le 10$  %.



- (1) Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint
- (2) FR4 PCB, mounting pad for collector 6 cm<sup>2</sup>
- (3) FR4 PCB, mounting pad for collector 1 cm<sup>2</sup>
- (4) FR4 PCB, standard footprint

Fig 1. Power derating curves

### 6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
ui(j a)	thermal resistance from	in free air	<u>[1]</u> -	-	350	K/W
	junction to ambient	<u>[</u>	[2] _	-	208	K/W
			[3] _	-	167	K/W
			[4] _	-	113	K/W
			[1][5]	-	50	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	45	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.
- [3] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- [4] Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.
- [5] Pulse test:  $t_p \le 10$  ms;  $\delta \le 10$  %.

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80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

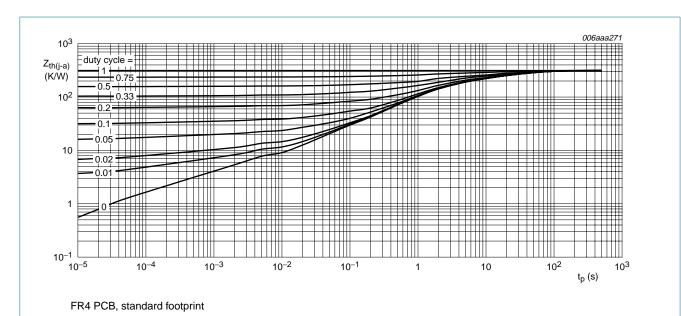


Fig 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

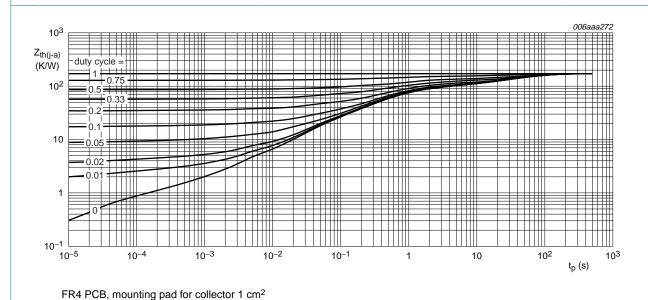


Fig 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

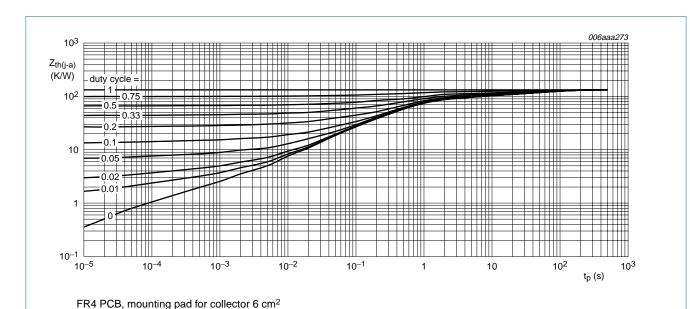


Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

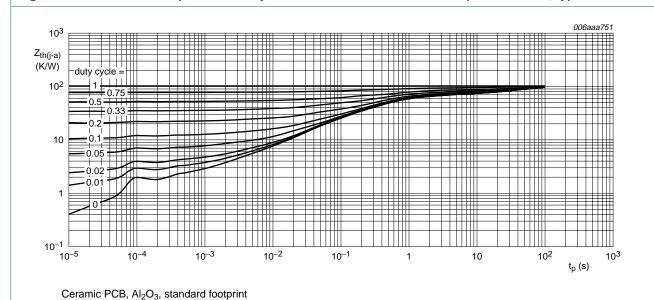


Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

#### **7**. **Characteristics**

Table 7. **Characteristics** 

 $T_{amb} = 25 \,^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$I_{CBO}$	collector-base cut-off	$V_{CB} = 80 \text{ V}; I_{E} = 0 \text{ A}$		-	-	100	nA
	current	$V_{CB} = 80 \text{ V; } I_E = 0 \text{ A;}$ $T_j = 150 ^{\circ}\text{C}$		-	-	50	μΑ
I <sub>CES</sub>	collector-emitter cut-off current	$V_{CE} = 64 \text{ V}; V_{BE} = 0 \text{ V}$		-	-	100	nA
I <sub>EBO</sub>	emitter-base cut-off current	$V_{EB} = 5 \text{ V}; I_{C} = 0 \text{ A}$		-	-	100	nA
h <sub>FE</sub>	DC current gain	$V_{CE} = 2 \text{ V}; I_{C} = 0.5 \text{ A}$		240	360	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 1 A	<u>[1]</u>	190	280	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 2 \text{ A}$	[1]	115	165	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 3 \text{ A}$	[1]	70	105	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 4 \text{ A}$	[1]	45	75	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 5 \text{ A}$	[1]	35	55	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 6 A	[1]	25	40	-	
$V_{\text{CEsat}}$	V <sub>CEsat</sub> collector-emitter	$I_C = 0.5 \text{ A}; I_B = 50 \text{ mA}$		-	40	55	mV
	saturation voltage	$I_C = 1 A; I_B = 50 mA$		-	80	105	mV
		$I_C = 2 \text{ A}; I_B = 200 \text{ mA}$	[1]	-	135	175	mV
		$I_C = 3 \text{ A}; I_B = 150 \text{ mA}$	[1]	-	215	275	mV
		$I_C = 3 \text{ A}; I_B = 300 \text{ mA}$	[1]	-	200	255	mV
		I <sub>C</sub> = 4 A; I <sub>B</sub> = 400 mA	[1]	-	265	335	mV
		$I_C = 5 A$ ; $I_B = 0.5 A$	[1]	-	335	415	mV
		$I_C = 6 \text{ A}; I_B = 0.6 \text{ A}$	[1]	-	400	505	mV
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_C = 2 \text{ A}; I_B = 200 \text{ mA}$	<u>[1]</u>	-	68	88	$m\Omega$
$V_{BEsat}$	base-emitter	$I_C = 0.5 \text{ A}; I_B = 50 \text{ mA}$		-	0.79	0.87	V
	saturation voltage	$I_C = 1 A$ ; $I_B = 50 \text{ mA}$		-	0.81	0.89	V
		I <sub>C</sub> = 1 A; I <sub>B</sub> = 100 mA	[1]	-	0.84	0.92	V
		$I_C = 3 A$ ; $I_B = 150 \text{ mA}$	[1]	-	0.92	1	V
		$I_C = 3 A$ ; $I_B = 300 \text{ mA}$	<u>[1]</u>	-	0.95	1.03	V
$V_{BEon}$	base-emitter turn-on voltage	$V_{CE} = 2 \text{ V}; I_{C} = 2 \text{ A}$		-	0.81	1	V

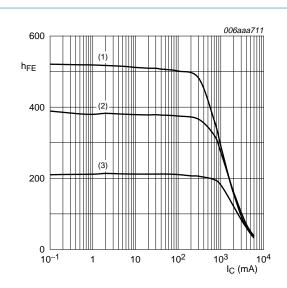
### 80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

 Table 7.
 Characteristics ...continued

 $T_{amb}$  = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$t_{d}$	delay time	$V_{CC} = 9.2 \text{ V}; I_C = 2 \text{ A};$	-	13	-	ns
t <sub>r</sub>	rise time	I <sub>Bon</sub> = 0.1 A; I <sub>Boff</sub> = -0.1 A	-	167	-	ns
t <sub>on</sub>	turn-on time		-	180	-	ns
ts	storage time		-	352	-	ns
t <sub>f</sub>	fall time		-	231	-	ns
t <sub>off</sub>	turn-off time		-	583	-	ns
f <sub>T</sub>	transition frequency	$V_{CE} = 10 \text{ V}; I_{C} = 100 \text{ mA};$ f = 100 MHz	-	140	-	MHz
C <sub>c</sub>	collector capacitance	$V_{CB} = 10 \text{ V}; I_E = i_e = 0 \text{ A};$ f = 1 MHz	-	18	-	pF

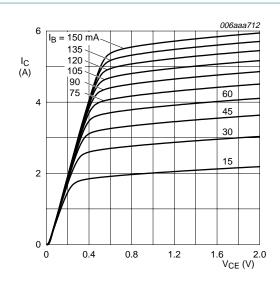
<sup>[1]</sup> Pulse test:  $t_p \le 300~\mu s;~\delta \le 0.02.$ 



$$V_{CE} = 2 V$$

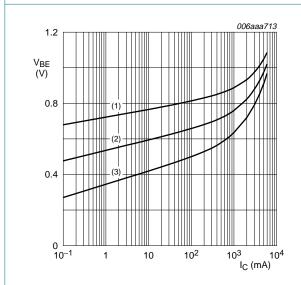
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \,^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

Fig 6. DC current gain as a function of collector current; typical values



 $T_{amb}$  = 25  $^{\circ}C$ 

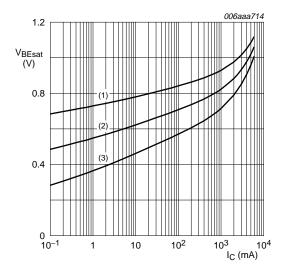
Fig 7. Collector current as a function of collector-emitter voltage; typical values



- V<sub>CE</sub> = 2 V
- (1)  $T_{amb} = -55 \,^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

**Product data sheet** 

Fig 8. Base-emitter voltage as a function of collector current; typical values

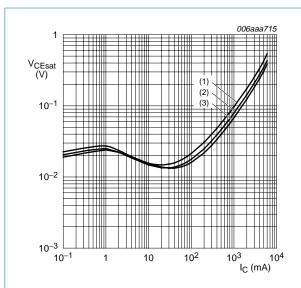


- $I_{\rm C}/I_{\rm B} = 20$
- (1)  $T_{amb} = -55 \,^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

Fig 9. Base-emitter saturation voltage as a function of collector current; typical values

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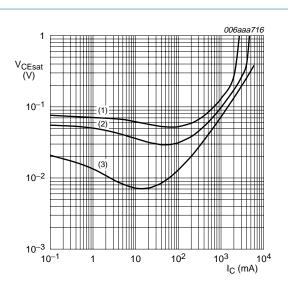
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$$I_{\rm C}/I_{\rm B} = 20$$

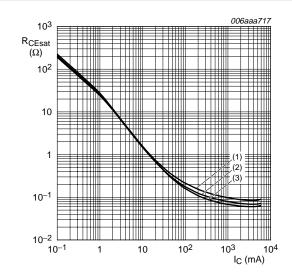
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

Fig 10. Collector-emitter saturation voltage as a function of collector current; typical values



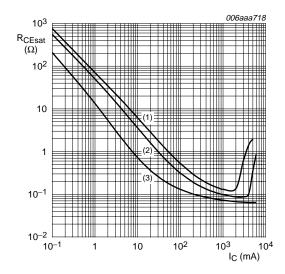
- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

Fig 11. Collector-emitter saturation voltage as a function of collector current; typical values



- $I_{\rm C}/I_{\rm B} = 20$
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \,^{\circ}C$
- (3)  $T_{amb} = -55 \,^{\circ}C$

Fig 12. Collector-emitter saturation resistance as a function of collector current; typical values



$$T_{amb} = 25 \, ^{\circ}C$$

- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

Fig 13. Collector-emitter saturation resistance as a function of collector current; typical values

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80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

### **Test information**

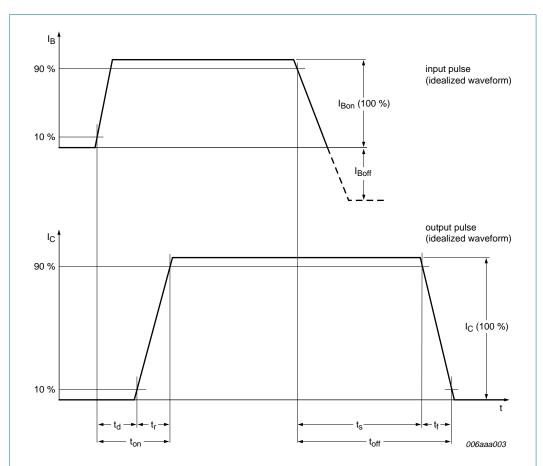
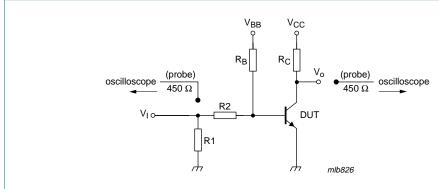


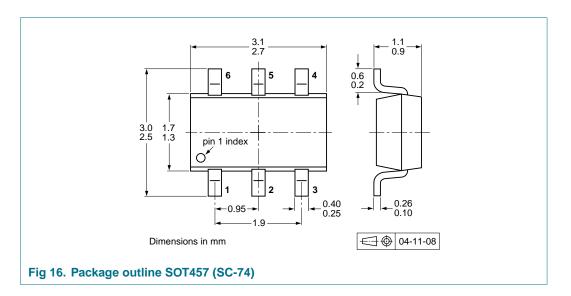
Fig 14. BISS transistor switching time definition



 $V_{CC}$  = 9.2 V;  $I_{C}$  = 2 A;  $I_{Bon}$  = 0.1 A;  $I_{Boff}$  = -0.1 A

Fig 15. Test circuit for switching times

### 9. Package outline



# 10. Packing information

Table 8. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

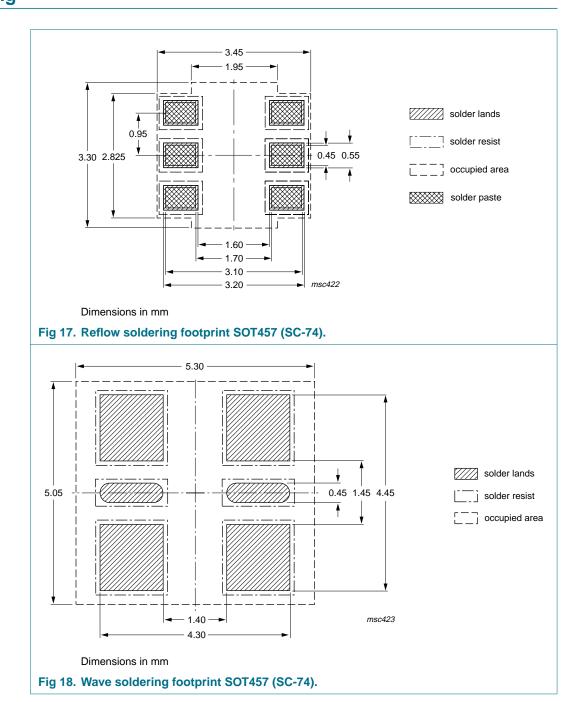
Type number	Package	Description		Packing quantity	
				3000	10000
PBSS304ND	SOT457	4 mm pitch, 8 mm tape and reel; T1	[2]	-115	-135
		4 mm pitch, 8 mm tape and reel; T2	[3]	-125	-165

[1] For further information and the availability of packing methods, see  $\underline{\text{Section 14}}$ .

[2] T1: normal taping

[3] T2: reverse taping

### 11. Soldering





# 12. Revision history

#### Table 9. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes		
PBSS304ND_2	20071217	Product data sheet	-	PBSS304ND_1		
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>					
	<ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>					
	<ul> <li><u>Table 6</u>: typing error for maximum value on 6 cm<sup>2</sup> footprint amended</li> </ul>					
	Section 13	"Legal information": update	ed			
PBSS304ND_1	20060407	Product data sheet	-	-		

### 13. Legal information

#### 13.1 **Data sheet status**

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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# PBSS304ND

### 80 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

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